

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/537,470	YANO ET AL.	
	<b>Examiner</b> Hieu P. Nguyen	<b>Art Unit</b> 2817	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner